



#### Product Summary

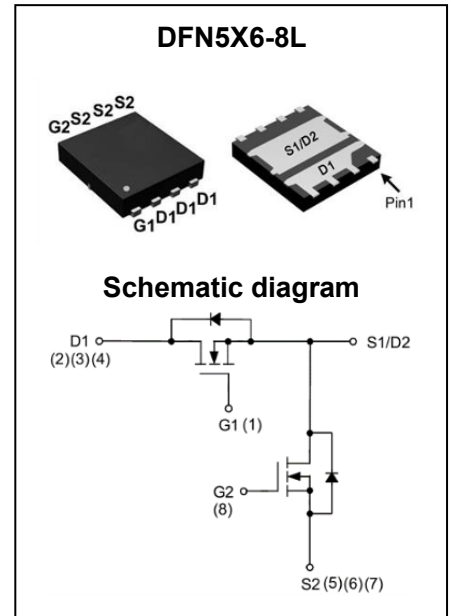
V <sub>(BR)DSS</sub>	R <sub>DS(on)TYP</sub>	I <sub>D</sub>
30V	5.1mΩ@10V(Channel1)	54A
	8.5mΩ@4.5V(Channel1)	
	5.1mΩ@10V(Channel2)	60A
	8.5mΩ@4.5V(Channel2)	

#### Feature

- Split Gate Trench Technology
- Low R<sub>DS(ON)</sub>
- Low Gate Charge
- Low Gate Resistance
- 100% UIS Tested

#### Application

- Power Management
- DC/DC Converter



#### Package Marking and Ordering Information

Part Number	Package	Marking	Packing	Reel Size	Tape Width	Qty
GPT051ND03LGK	DFN5X6-8L	T051ND03L	Reel & Tape	330mm	12mm	5000pcs

#### ABSOLUTE MAXIMUM RATINGS (T<sub>A</sub> = 25°C unless otherwise noted)

Parameter	Symbol	Channel1	Channel2	Unit
Drain-Source Voltage	V <sub>DS</sub>	30		V
Gate-Source Voltage	V <sub>GS</sub>	±20		V
Continuous Drain Current <sup>1</sup>	I <sub>D</sub>	T <sub>C</sub> = 25°C	50	55
		T <sub>C</sub> = 100°C	31.5	34.5
Pulsed Drain Current <sup>2</sup>	I <sub>DM</sub>	200	220	A
Single Pulsed Avalanche Current <sup>3</sup>	I <sub>AS</sub>	15	17	A
Single Pulsed Avalanche Energy <sup>3</sup>	E <sub>AS</sub>	56	72	mJ
Power Dissipation <sup>5</sup>	P <sub>D</sub>	25	31.25	W
T <sub>C</sub> = 25°C				
Thermal Resistance from Junction to Ambient <sup>6</sup>	R <sub>θJA</sub>	48	45	°C/W
Thermal Resistance from Junction to Case	R <sub>θJC</sub>	5	4	°C/W
Operating Junction and Storage Temperature Range	T <sub>J</sub> , T <sub>STG</sub>	-55~ +150		°C

## MOSFET ELECTRICAL CHARACTERISTICS ( $T_A = 25^\circ\text{C}$ unless otherwise noted)

### Channel1:

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Off Characteristics</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = 250\mu A$	30			V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 30V, V_{GS} = 0V$			1	$\mu A$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
<b>On Characteristics<sup>4</sup></b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.0	1.5	2.2	V
Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 15A$		5.1	6.5	m $\Omega$
		$V_{GS} = 4.5V, I_D = 10A$		8.0	11	
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{iss}$	$V_{DS} = 15V, V_{GS} = 0V, f = 1MHz$		608		pF
Output Capacitance	$C_{oss}$			350		
Reverse Transfer Capacitance	$C_{rss}$			14		
Gate Resistance	$R_g$	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$		1.3		$\Omega$
<b>Switching Characteristics</b>						
Total Gate Charge	$Q_g$	$V_{DS} = 15V, V_{GS} = 10V, I_D = 20A$		11.3		nC
Gate-Source Charge	$Q_{gs}$			1.8		
Gate-Drain Charge	$Q_{gd}$			2.2		
Gate Plateau Voltage	$V_{plateau}$			2.8		V
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 15V, V_{GS} = 10V, I_D = 20A,$ $R_G = 3\Omega$		4		ns
Turn-On Rise Time	$t_r$			5		
Turn-Off Delay Time	$t_{d(off)}$			32		
Turn-Off Fall Time	$t_f$			15		
<b>Source-Drain Diode Characteristics</b>						
Diode Forward Voltage <sup>4</sup>	$V_{SD}$	$V_{GS} = 0V, I_S = 2A$			1.2	V
Diode Continuous Forward Current <sup>1</sup>	$I_S$	$T_C = 25^\circ\text{C}$			50	A
Diode Pulse Forward Current <sup>2</sup>	$I_{SM}$	$T_C = 25^\circ\text{C}$			200	A
Diode Reverse Recovery Time	$t_{rr}$	$I_F = 15A, dI/dt = 100A/\mu s$		12		ns
Diode Reverse Recovery Charge	$Q_{rr}$	$I_F = 15A, dI/dt = 100A/\mu s$		3.2		nC

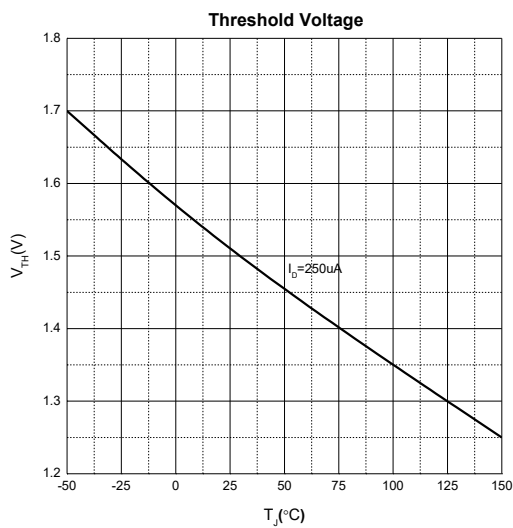
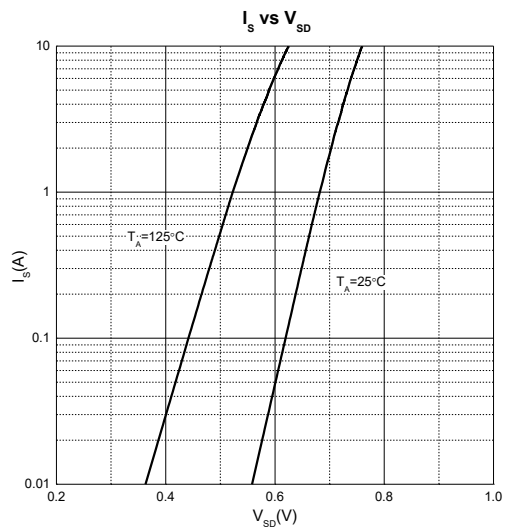
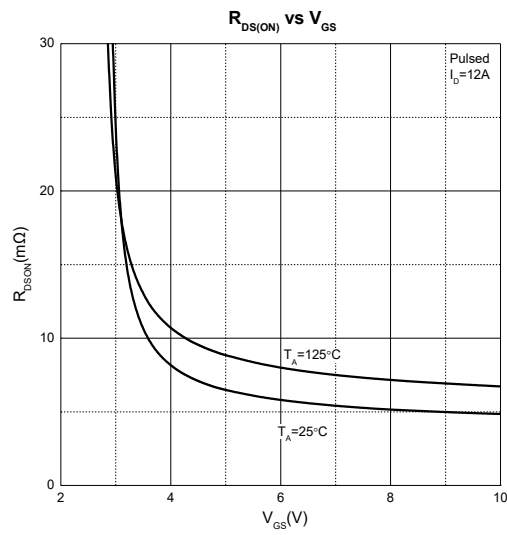
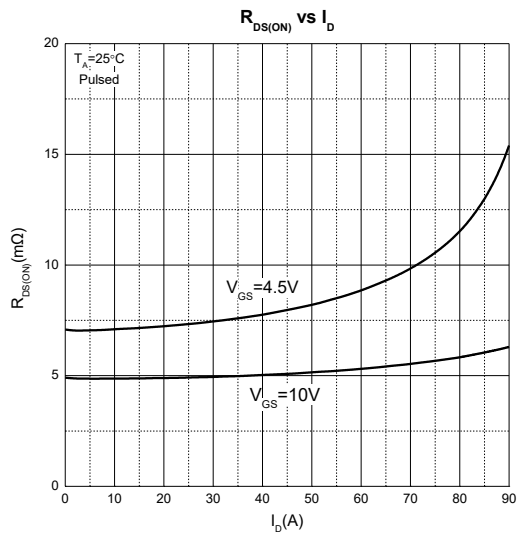
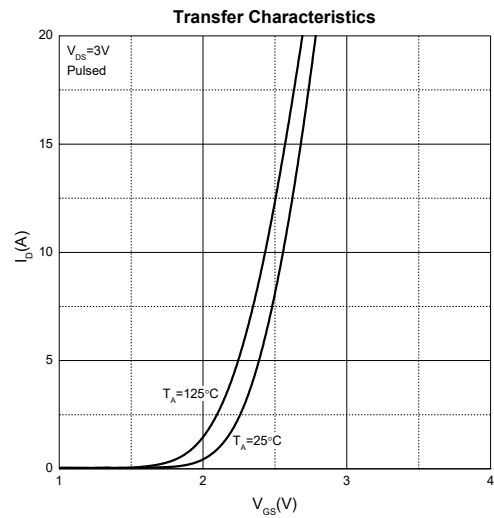
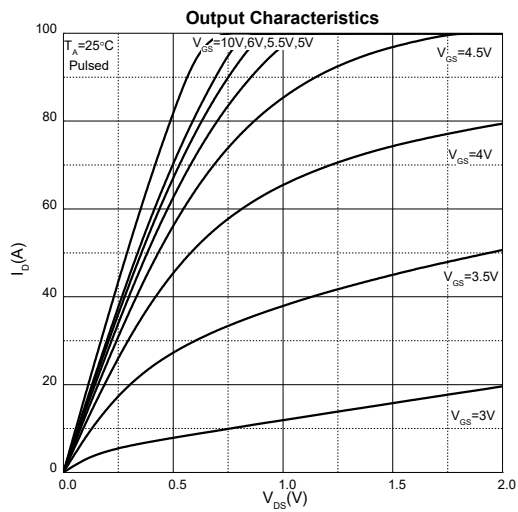
**Channel2:**

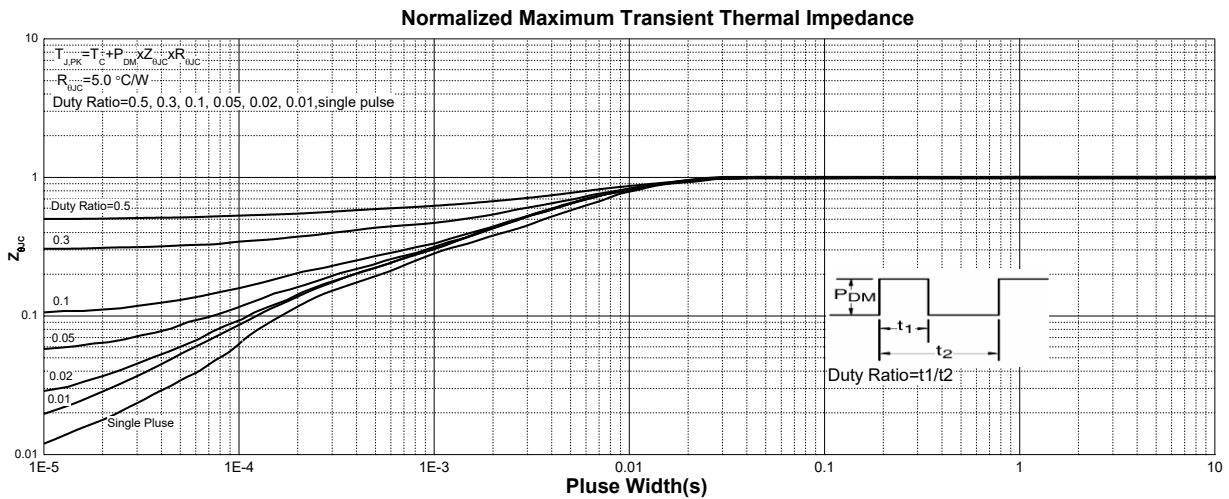
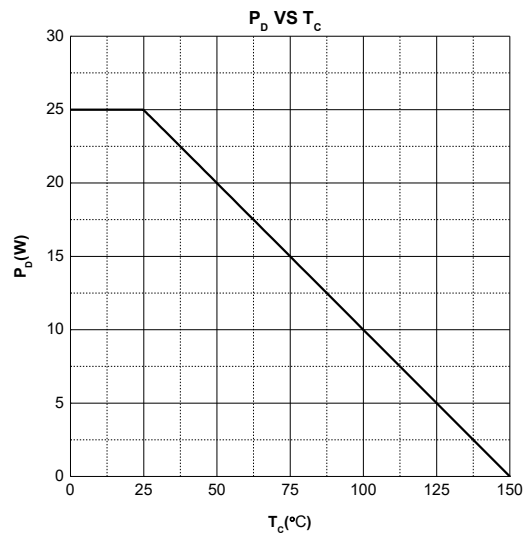
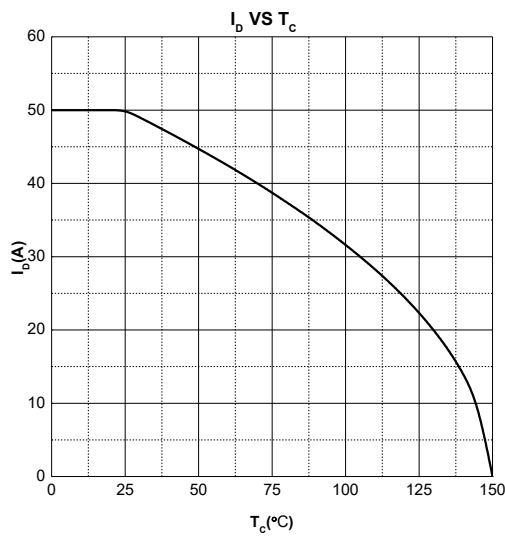
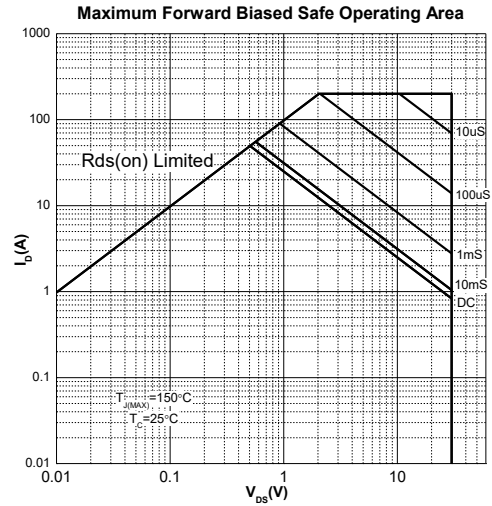
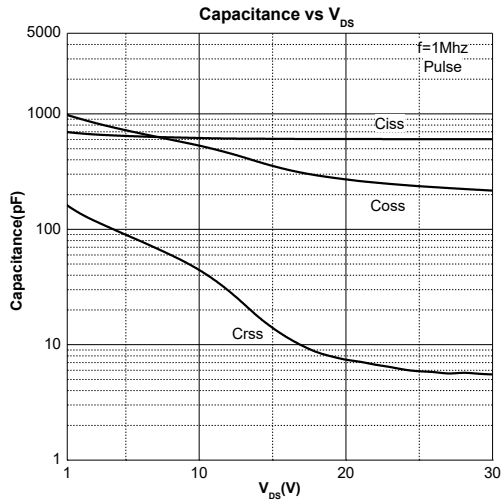
Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Off Characteristics</b>						
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Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 30V, V_{GS} = 0V$			1	$\mu A$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$			$\pm 100$	nA
<b>On Characteristics<sup>4</sup></b>						
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu A$	1.0	1.5	2.2	V
Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10V, I_D = 30A$		5.1	6.5	m $\Omega$
		$V_{GS} = 4.5V, I_D = 15A$		8.0	11	
<b>Dynamic Characteristics</b>						
Input Capacitance	$C_{iss}$	$V_{DS} = 15V, V_{GS} = 0V, f = 1MHz$		608		pF
Output Capacitance	$C_{oss}$			350		
Reverse Transfer Capacitance	$C_{rss}$			14		
Gate Resistance	$R_g$	$V_{DS} = 0V, V_{GS} = 0V, f = 1MHz$		1.3		$\Omega$
<b>Switching Characteristics</b>						
Total Gate Charge	$Q_g$	$V_{DS} = 15V, V_{GS} = 10V, I_D = 20A$		11.3		nC
Gate-Source Charge	$Q_{gs}$			1.8		
Gate-Drain Charge	$Q_{gd}$			2.2		
Gate Plateau Voltage	$V_{plateau}$			2.8		V
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 15V, V_{GS} = 10V, I_D = 20A, R_G = 3\Omega$		4		ns
Turn-On Rise Time	$t_r$			5		
Turn-Off Delay Time	$t_{d(off)}$			32		
Turn-Off Fall Time	$t_f$			15		
<b>Source-Drain Diode Characteristics</b>						
Diode Forward Voltage <sup>4</sup>	$V_{SD}$	$V_{GS} = 0V, I_S = 1A$			1.2	V
Diode Continuous Forward Current <sup>1</sup>	$I_S$	$T_C = 25^\circ C$			55	A
Diode Pulse Forward Current <sup>2</sup>	$I_{SM}$	$T_C = 25^\circ C$			220	A
Diode Reverse Recovery Time	$t_{rr}$	$I_F = 15A, dI/dt = 100A/\mu s$		12		ns
Diode Reverse Recovery Charge	$Q_{rr}$	$I_F = 15A, dI/dt = 100A/\mu s$		3.2		nC

**Notes:**

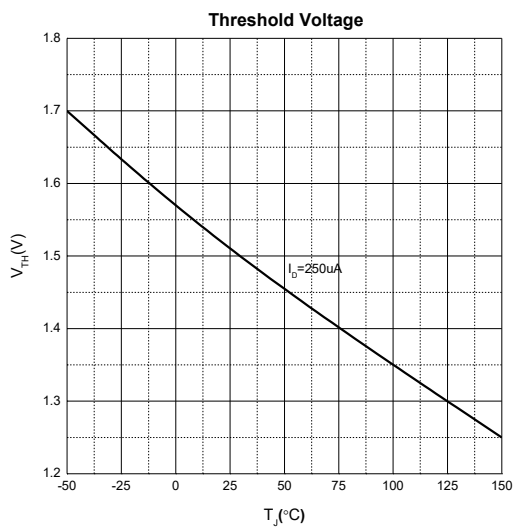
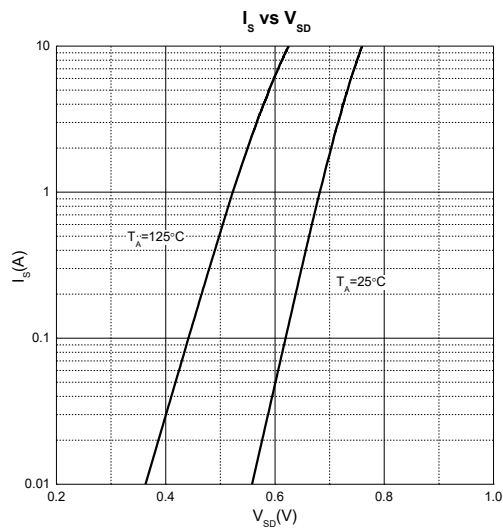
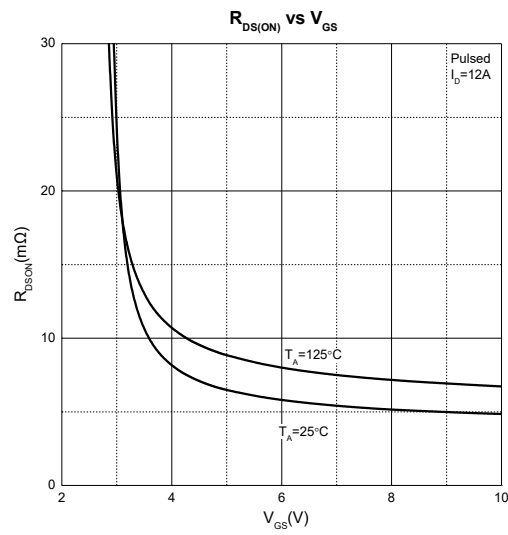
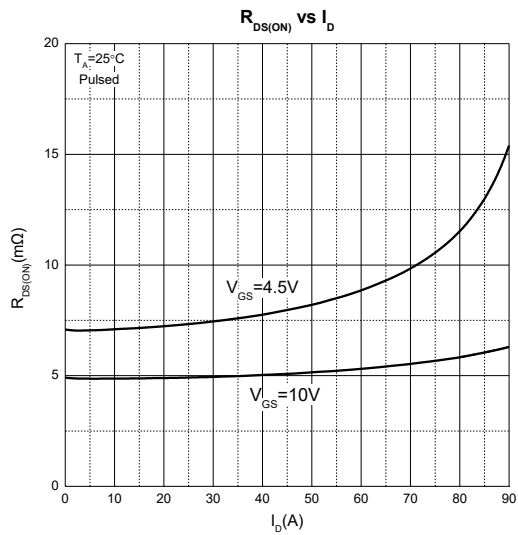
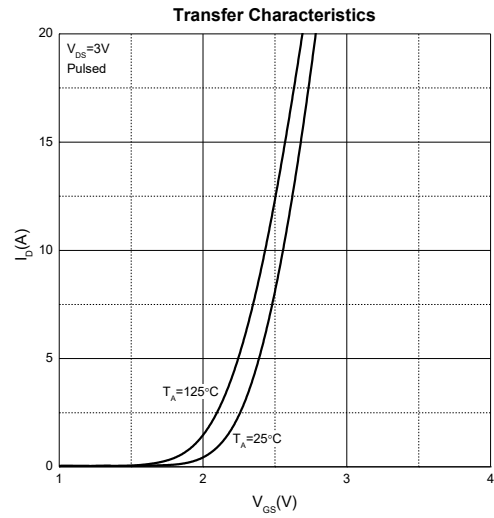
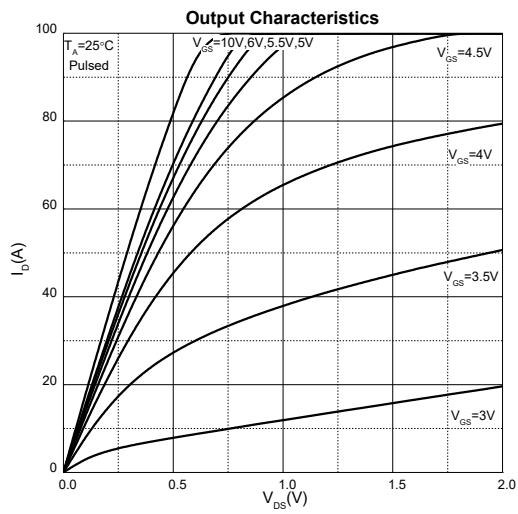
- 1.The maximum current rating is limited by package. And device mounted on a large heatsink.
- 2.Pulse Test: Pulse Width  $\leq 10\mu s$ , duty cycle  $\leq 1\%$ .
- 3.EAS condition:  $V_{DD} = 30V, V_{GS} = 10V, L = 0.5mH, R_G = 25\Omega$  Starting  $T_J = 25^\circ C$ .
- 4.Pulse Test: Pulse Width  $\leq 300\mu s$ , duty cycle  $\leq 2\%$ .
- 5.The power dissipation  $P_D$  is limited by  $T_{J(MAX)} = 150^\circ C$ . And device mounted on a large heatsink.
- 6.Device mounted on  $1in^2$  FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ C$ .

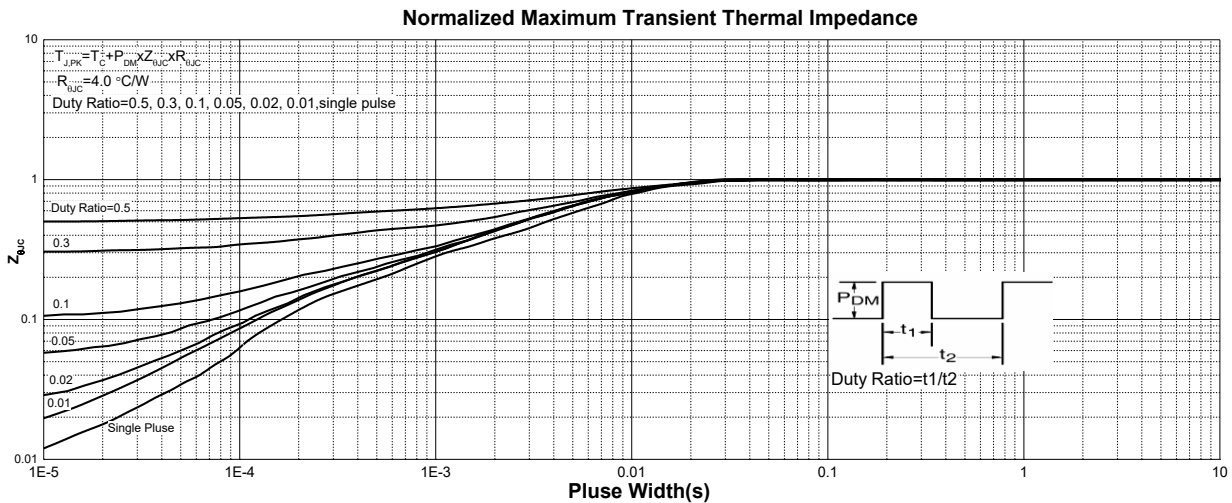
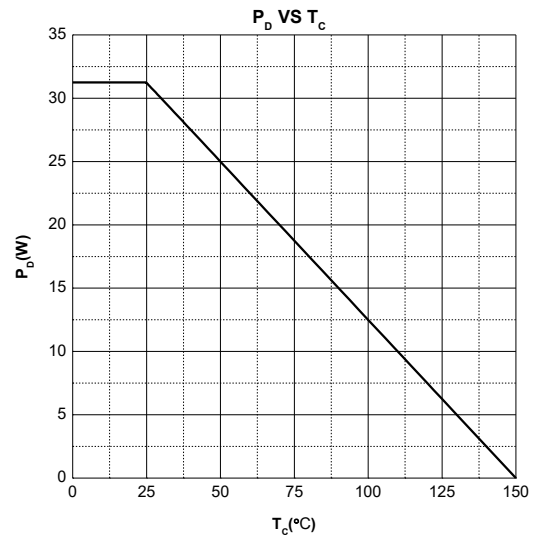
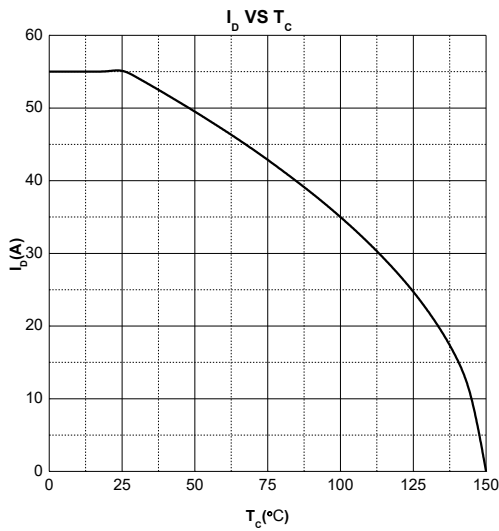
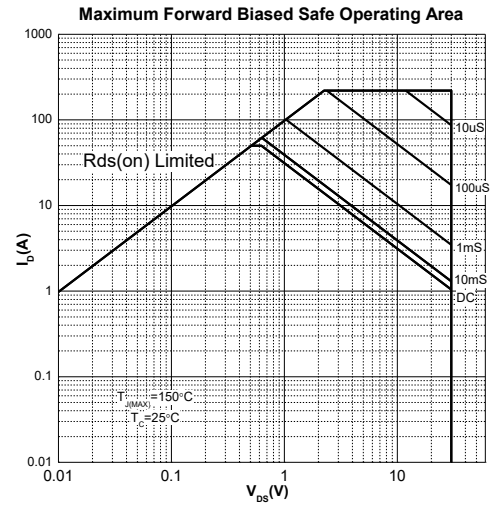
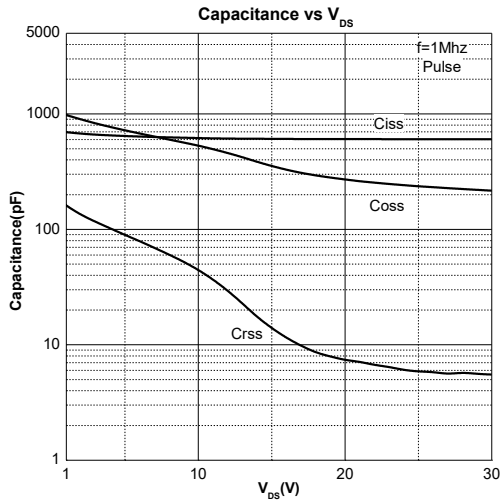
## Channel1 Typical Characteristics





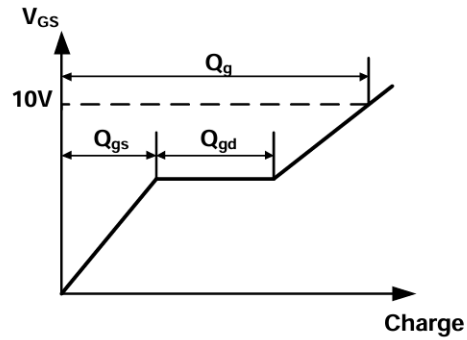
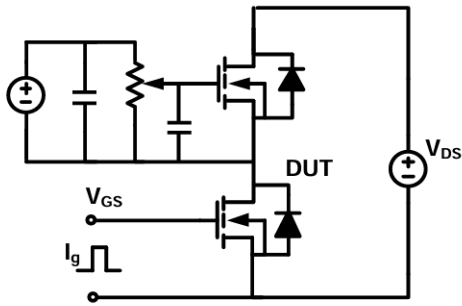
## Channel2 Typical Characteristics



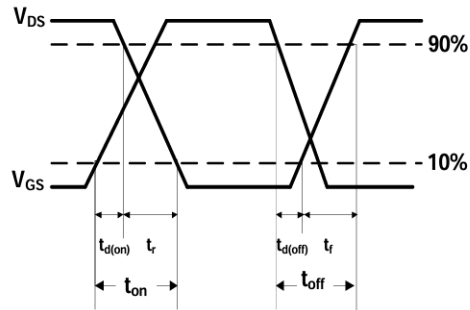
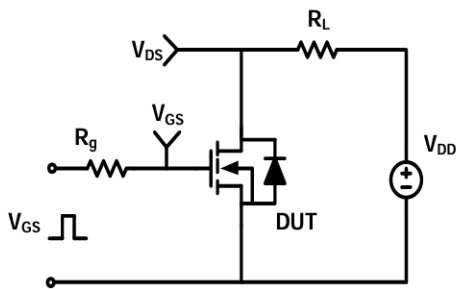


**Test Circuit**

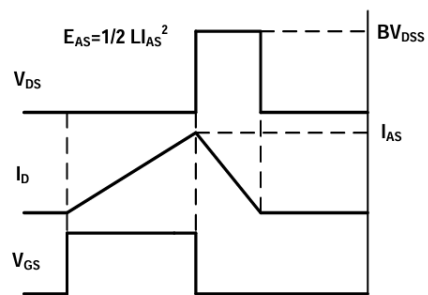
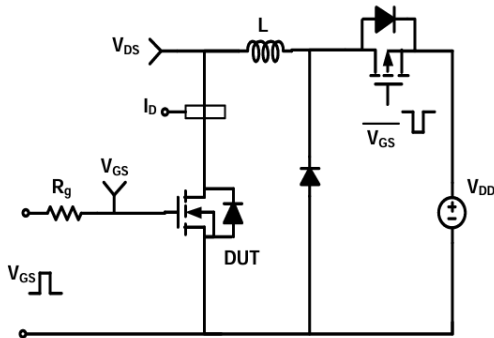
**Gate Charge Test Circuit & Waveform**



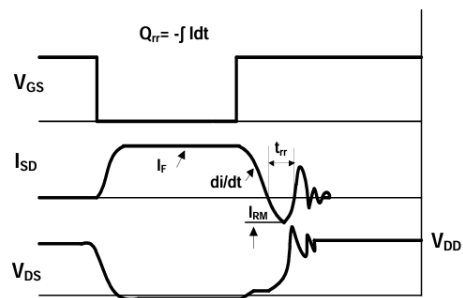
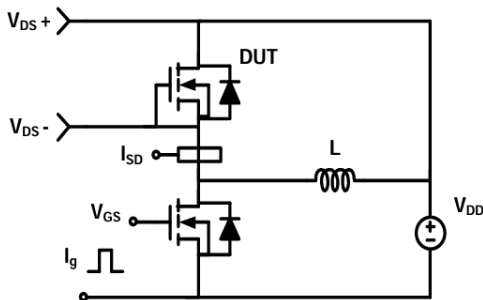
**Resistive Switching Test Circuit & Waveform**



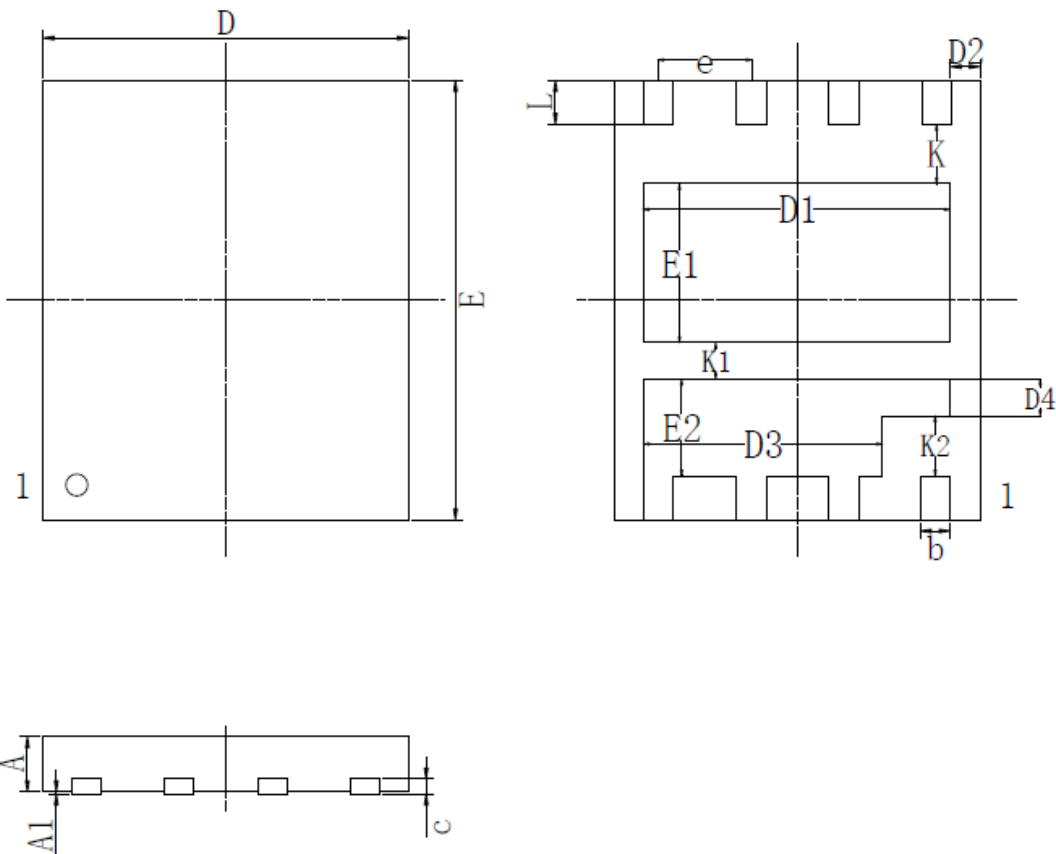
**Unclamped Inductive Switching (UIS) Test Circuit & Waveform**



**Diode Recovery Test Circuit & Waveform**



## DFN5X6-8L Package Information



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.700	0.800	0.028	0.031
A1	0	0.050	0.000	0.002
c	0.203REF		0.008REF	
D	4.95	5.05	0.195	0.199
E	5.95	6.05	0.234	0.238
D1	4.1	4.3	0.161	0.169
D2	0.390REF		0.015REF	
D3	3.17	3.37	0.125	0.133
D4	0.45	0.55	0.018	0.022
E1	2.07	2.27	0.081	0.089
E2	1.22	1.42	0.048	0.056
K	0.81BSC		0.032BSC	
K1	0.50BSC		1.032BSC	
K2	0.82BSC		2.032BSC	
b	0.36	0.46	0.014	0.018
e	1.27BSC		0.050BSC	
L	0.55	0.65	0.022	0.026

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